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And

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| <u>L12</u> | l10 and l11 | 0 | <u>L12</u> |
| <u>L11</u> | ((linear adj frequency adj modulat\$3) or lfm) | 2 | <u>L11</u> |
| <u>L10</u> | tag\$1 or responder\$1 or transponder\$1 | 1065 | <u>L10</u> |

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|-----------|--|-------|-----------|
| <u>L9</u> | l4 and chirp\$4.ti,ab. | 23 | <u>L9</u> |
| <u>L8</u> | l2 and chirp\$4.ti,ab. | 1 | <u>L8</u> |
| <u>L7</u> | l6 not l3 | 7 | <u>L7</u> |
| <u>L6</u> | l4 and l5 | 9 | <u>L6</u> |
| <u>L5</u> | ((linear adj frequency adj modulat\$3) or lfm) | 1271 | <u>L5</u> |
| <u>L4</u> | (tag\$1 or responder\$1 or transponder\$1).ti,ab. | 52952 | <u>L4</u> |
| <u>L3</u> | ((linear adj frequency adj modulat\$3) or lfm) and l2 | 2 | <u>L3</u> |
| <u>L2</u> | (tag\$1 or responder\$1 or transponder\$1).ti,ab. and l1 | 713 | <u>L2</u> |
| <u>L1</u> | radar\$1.ti,ab. | 42996 | <u>L1</u> |

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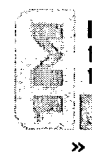
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frequency In: All Fields

And

modulation In: All Fields

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1 An active tagging system using circular-polarization modulation
Kossel, M.A.; Kung, R.; Benedickter, H.; Biichtokd, W.;

Microwave Theory and Techniques, IEEE Transactions on , Volume: 47 , Issue 12 , Dec. 1999

Pages:2242 - 2248

[\[Abstract\]](#)
[\[PDF Full-Text \(388 KB\)\]](#)
IEEE JNL
2 An overview of backscattered radio frequency identification system (RFID)
Rao, K.V.S.;

Microwave Conference, 1999 Asia Pacific , Volume: 3 , 30 Nov.-3 Dec. 1999

Pages:746 - 749 vol.3

[\[Abstract\]](#)
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IEEE CNF
3 Optimal tag pattern validation using magnetic resonance imaging
Denney, T.S., Jr.; Prince, J.L.; Lopez, M.J.; McVeigh, E.R.;

Image Processing, 1994. Proceedings. ICIP-94., IEEE International Conference , Volume: 1 , 13-16 Nov. 1994

Pages:881 - 885 vol.1

[\[Abstract\]](#)
[\[PDF Full-Text \(372 KB\)\]](#)
IEEE CNF
4 Microwave backscatter modulation systems
Kossel, M.; Benedickter, H.R.; Peter, R.; Bachtold, W.;

Microwave Symposium Digest., 2000 IEEE MTT-S International , Volume: 3 , June 2000

Pages:1427 - 1430 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(292 KB\)\]](#) IEEE CNF

5 Optimization of inductive RFID technology

Chen, S.C.Q.; Thomas, V.;

Electronics and the Environment, 2001. Proceedings of the 2001 IEEE International Symposium on , 7-9 May 2001

Pages:82 - 87

[\[Abstract\]](#) [\[PDF Full-Text \(416 KB\)\]](#) IEEE CNF

6 Passive 5.8-GHz radio-frequency identification tag for monitoring of pipe

Strassner, B.; Kai Chang;

Microwave Theory and Techniques, IEEE Transactions on , Volume: 51 , Issue: 2 , Feb. 2003

Pages:356 - 363

[\[Abstract\]](#) [\[PDF Full-Text \(577 KB\)\]](#) IEEE JNL

7 Fully integrated passive UHF RFID transponder IC with 16.7-/spl mW minimum RF input power

Karthauss, U.; Fischer, M.;

Solid-State Circuits, IEEE Journal of , Volume: 38 , Issue: 10 , Oct. 2003

Pages:1602 - 1608

[\[Abstract\]](#) [\[PDF Full-Text \(503 KB\)\]](#) IEEE JNL

8 A global SAW ID tag with large data capacity

Hartmann, C.S.;

Ultrasonics Symposium, 2002. Proceedings. 2002 IEEE , Volume: 1 , 8-11 Oct 2002

Pages:65 - 69 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(395 KB\)\]](#) IEEE CNF

9 Short range UHF telemetry system using passive transponders for vehicle ID and status information

Koelle, A.R.;

Automotive Applications of Electronics, 1988., IEEE Workshop on , 19 Oct. 1988

Pages:34 - 38

[\[Abstract\]](#) [\[PDF Full-Text \(440 KB\)\]](#) IEEE CNF

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